

# Probability and Random Processes (15B11MA301)

## Lecture-23

(**Content Covered: MTTF, Conditional Reliability**)



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## Mean time to failure (MTTF)

- The expected value of the time the failure  $T$ , denoted by  $E(T)$  and variance of  $T$ , denoted by  $\sigma_T^2$  are two important parameters frequently used to characterize reliability.
- $E(T)$  is called *mean time to failure and denoted by MTTF*.

$$\begin{aligned} MTTF = E(T) &= \int_0^{\infty} t f(t) dt \\ &= - \int_0^{\infty} t R'(t) dt \\ &= -[tR(t)]_0^{\infty} + \int_0^{\infty} R(t) dt \end{aligned} \tag{1}$$

On integrating by parts

$$\text{Now } [tR(t)]_{t=\infty} = \left[ te^{-\int_0^t \lambda(t)dt} \right]_{t=\infty} = \left[ \frac{t}{e^{\int_0^t \lambda(t)dt}} \right]_{t=\infty} = 0$$

and  $[tR(t)]_{t=0} = 0 \times R(0) = 0 \times 1 = 0$

Using (1) and above results we have MTTF and variance as:

$$\text{MTTF} = \int_0^{\infty} R(t)dt$$

$$\text{Var}(T) \sigma_T^2 = E\{T - E(T)\}^2 \text{ or } E(T^2) - \{E(t)\}^2$$

$$= \int_0^{\infty} t^2 f(t)dt - (MTTF)^2$$

# Conditional Reliability

- Conditional reliability is used to describe the reliability of a component or system following a wear-in period (burn-in period) or after a warranty period.

- It is defined as
$$\begin{aligned} R(t/T_0) &= P\{T > T_0 + t / T > T_0\} \\ &= \frac{P\{T > T_0 + t\}}{P\{T > T_0\}} = \frac{R(T_0 + t)}{R(T_0)} \\ &= \frac{e^{-\int_0^{T_0+t} \lambda(t) dt}}{e^{-\int_0^{T_0} \lambda(t) dt}} = e^{-\left[\int_0^{T_0+t} \lambda(t) dt - \int_0^{T_0} \lambda(t) dt\right]} \\ &= e^{-\int_{T_0}^{T_0+t} \lambda(t) dt} \end{aligned}$$

# Design Life

- Design life is the time to failure that corresponds to a specified reliability.
- It is usually denoted by  $t_D$ .

**Example 1:** The density function of the time to failure in years of the gizmos (for use on widgets) manufactured by a certain company is given by

$$f(t) = \frac{200}{(t+10)^3}, t \geq 0$$

- (a) Derive the reliability function and determine the reliability for the first year of operation.
- (b) Compute the MTTF.
- (c) What is the design life for a reliability 0.95?
- (d) Will a one-year burn-in period improve the reliability in part (a)? If so, what is the new reliability?

**Solution:**

$$(a) \quad f(t) = \frac{200}{(t+10)^3}, \quad t \geq 0$$

$$R(t) = \int_t^{\infty} f(t)dt = \left[ \frac{-100}{(t+10)^2} \right]_t^{\infty} = \frac{100}{(t+10)^2}$$

$$\therefore R(1) = \frac{100}{(1+10)^2} = 0.8264.$$

$$(b) \quad \text{MTTF} = \int_0^{\infty} R(t)dt = \int_0^{\infty} \frac{100}{(t+10)^2} dt$$
$$= \left( \frac{-100}{t+10} \right)_0^{\infty} = 10 \text{ years.}$$



(c) Here,  $R=0.95$

$$\therefore \frac{100}{(t+10)^2} = 0.95$$

$$\text{i.e., } (t_D + 10)^2 = 100.2632$$

$$\therefore t_D = 0.2598 \text{ year or 95 days}$$

$$(d) \quad R(t/1) = \frac{R(t+1)}{R(1)} = \frac{100}{(t+11)^2} \div \frac{100}{11^2} = \frac{121}{(t+11)^2}$$

$$\text{Now } R(t/1) > R(t), \text{ if } \frac{121}{(t+11)^2} > \frac{100}{(t+10)^2}$$

$$\text{i.e., if } \frac{(t+10)^2}{(t+11)^2} > \frac{100}{121}$$

$$\text{i.e., if } \frac{t+10}{t+11} > \frac{10}{11}$$

i.e.,  $11t > 10t$ , which is true, as  $t \geq 0$

$\therefore$  One year burn-in period will improve the reliability.

$$\text{Now } R(1/1) = \frac{121}{(1+11)^2} = 0.8403 > 0.8264.$$

**Example 2:** The time to failure in operating hours of a critical solid-state power unit has the hazard rate function

$$\lambda(t) = 0.003 \left( \frac{t}{500} \right)^{0.5}, \text{ for } t \geq 0.$$

- (a) Determine the design life if a reliability of 0.90 is desired.
- (b) Compute the MTTF.
- (c) Given that the unit has operated for 50 hours, what is the probability that it will survive a second 50 hours of operation?

**Solution: (a)**

$$R(t_D) = 0.90$$

$$\exp \left[ - \int_0^{t_D} 0.003 \left( \frac{t}{500} \right)^{0.5} dt \right] = 0.90$$

$$- \int_0^{t_D} \frac{0.003}{\sqrt{500}} t^{1/2} dt = -0.10536$$

i.e., 
$$\frac{0.003}{\sqrt{500}} \times \frac{2}{3} t_D^{3/2} = 0.10536$$

$$\therefore t_D = \left\{ \frac{3 \times \sqrt{500} \times 0.10536}{2 \times 0.003} \right\}^{2/3} = 111.54 \text{ hours.}$$

(b)

$$\begin{aligned}\text{MTTF} &= \int_0^{\infty} R(t) dt \\&= \int_0^{\infty} e^{-\left(\frac{0.003}{\sqrt{500}} \times \frac{2}{3} \times t^{3/2}\right)} dt \\&= \int_0^{\infty} e^{-at^{3/2}} dt, \text{ where } a = \frac{0.003 \times 2}{3 \times \sqrt{500}} \\&= \int_0^{\infty} e^{-x} \cdot \frac{2}{3a^{2/3}} x^{-1/3} dx, \text{ on putting } x = at^{3/2} \\&= \frac{2}{3a^{2/3}} \Gamma(2/3) = \frac{2}{3a^{2/3}} \frac{3}{2} \Gamma(5/3) \\&= \frac{0.9033}{a^{2/3}}, \text{ from the table of values of Gamma function.} \\&= 45.65 \text{ hours.}\end{aligned}$$

(c)

$$\begin{aligned}P(T \geq 100/T \geq 50) &= \frac{P(T \geq 100)}{P(T \geq 50)} = \frac{R(100)}{R(50)} \\&= \exp \left[ \geq \int_{50}^{100} \lambda(t) dt \right] \\&= \exp \left[ \left\{ -\frac{0.002}{\sqrt{500}} \times 100^{3/2} \right\} - \left\{ \frac{-0.002}{\sqrt{500}} \times 50^{3/2} \right\} \right] \\&= \exp[ \{-0.08944\} - \{-0.03162\} ] \\&= 0.9438\end{aligned}$$

## Practice Question

Question: A logic circuit is known to have a decreasing failure rate of the form  $\lambda(t) = \frac{1}{2\sqrt{t}}$  per year, where  $t$  is in years.

- (a) If the design life is one year, what is the reliability?
- (b) If the component undergoes wear in for one month before being put into operation, what will the reliability be for a one-year design life?

Ans: a) 0.905 b) 0.928

## References

1. Veerarajan, T., Probability, Statistics and Random Processes, 3<sup>rd</sup> Ed. Tata McGraw-Hill, 2008.
2. Ghahramani, S., Fundamentals of Probability with Stochastic Processes, Pearson, 2005.
3. Papoulis, A. and Pillai, S.U., Probability, Random Variables and Stochastic Processes, Tata McGraw-Hill, 2002.
4. Miller, S., Childers, D., Probability and Random Processes, Academic Press, 2012.